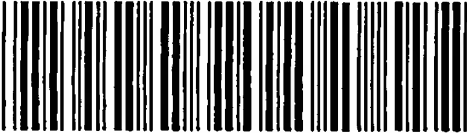


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/079,334	DE ET AL.	
	Examiner	Art Unit	
	Jason M. Perilla	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	147	8/16/2007	JP
	150	8/16/2007	JP
	148	8/16/2007	JP
370	147	8/16/2007	JP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	147	8/16/2007	JP

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East USPAT/USPGPUB	8/16/2007	JP
Inventor Name Search EAST/EDAN	8/16/2007	JP